# BLM7G1822S-20PB; BLM7G1822S-20PBG

**LDMOS 2-stage power MMIC** 

Rev. 1 — 19 December 2013

Objective data sheet

### 1. Product profile

### 1.1 General description

The BLM7G1822S-20PB and BLM7G1822S-20PBG are dual path, 2-stage power MMICs using NXP's state of the art GEN7 LDMOS technology. These multiband devices are perfectly suited as general purpose driver or small cell final in the frequency range from 1805 MHz to 2170 MHz. Available in gull wing or flat lead outline.

#### Table 1. Application performance

Typical RF performance at  $T_{case} = 25$  °C;  $I_{Dq1} = < tbd>$ ;  $I_{Dq2} = < tbd>$ . Test signal: 3GPP test model 1; 64 DPCH; clipping at 46 %; PAR = 8.4 dB at 0.01% probability on CCDF per carrier; carrier spacing = 5 MHz; per section unless otherwise specified in a class-AB

production circuit.

Test signal	f	V <sub>DS</sub>	P <sub>L(AV)</sub>	Gp	$\eta_{D}$	ACPR
	(MHz)	(V)	(W)	(dB)	(%)	(dBc)
2-carrier W-CDMA	2140	28	0.5	31.5	12	<tbd></tbd>

#### 1.2 Features and benefits

- Designed for broadband operation (frequency 1805 MHz to 2170 MHz)
- High path-to-path isolation enabling multiple combinations
- Integrated temperature compensated bias
- Biasing of individual stages is externally accessible
- Integrated ESD protection
- Excellent thermal stability
- High power gain
- On-chip matching for ease of use
- Compliant to Directive 2002/95/EC, regarding restriction of hazardous substances (RoHS)

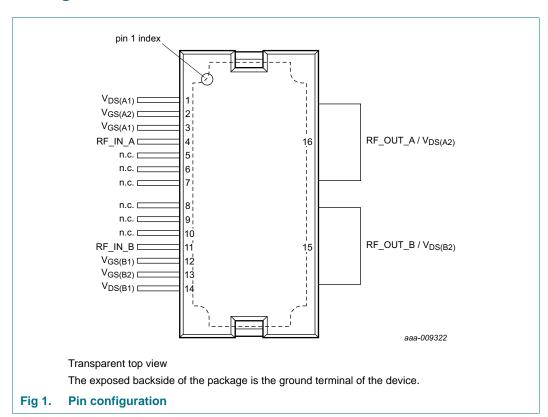
#### 1.3 Applications

- RF power MMIC for W-CDMA base stations in the 1805 MHz to 2170 MHz frequency range. Possible circuit topologies are the following as also depicted in <u>Section 8.1</u>:
  - Dual path or single ended
  - Doherty
  - Quadrature combined
  - Push-pull



### 2. Pinning information

### 2.1 Pinning



### 2.2 Pin description

Table 2. Pin description

Symbol	Pin	Description
V <sub>DS(A1)</sub>	1	drain-source voltage of stage A1
V <sub>GS(A2)</sub>	2	gate-source voltage of stage A2
V <sub>GS(A1)</sub>	3	gate-source voltage of stage A1
RF_IN_A	4	RF input path A
n.c.	5	not connected
n.c.	6	not connected
n.c.	7	not connected
n.c.	8	not connected
n.c.	9	not connected
n.c.	10	not connected
RF_IN_B	11	RF input path of B
V <sub>GS(B1)</sub>	12	gate-source voltage of stage B1
V <sub>GS(B2)</sub>	13	gate-source voltage of stage B2
V <sub>DS(B1)</sub>	14	drain-source voltage of stage B1

 Table 2.
 Pin description ...continued

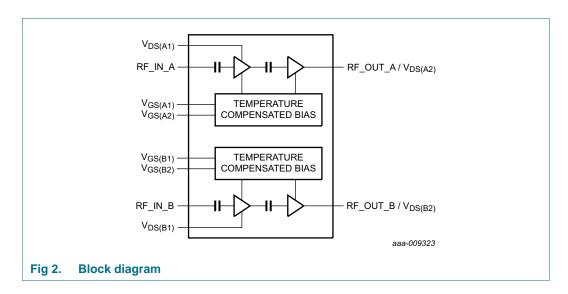
Symbol	Pin	Description
RF_OUT_B/V <sub>DS(B2)</sub>	15	RF output path B / drain-source voltage of stage B2
RF_OUT_A/V <sub>DS(A2)</sub>	16	RF output path A / drain-source voltage of stage A2
GND	flange	RF ground

### 3. Ordering information

Table 3. Ordering information

Type number	Package					
	Name	Description	Version			
BLM7G1822S-20PB	HSOP16F	plastic, heatsink small outline package; 16 leads (flat)	SOT1211-1			
BLM7G1822S-20PBG	HSOP16	plastic, heatsink small outline package; 16 leads	SOT1212-1			

### 4. Block diagram



## 5. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions		Min	Max	Unit
$V_{DS}$	drain-source voltage			-	65	V
$V_{GS}$	gate-source voltage			-0.5	+13	V
T <sub>stg</sub>	storage temperature			-65	+150	°C
Tj	junction temperature		[1]	-	225	°C
T <sub>case</sub>	case temperature			-	150	°C

Continuous use at maximum temperature will affect the reliability, for details refer to the on-line MTF calculator.

### 6. Thermal characteristics

Table 5. Thermal characteristics

Measured for total device.

Symbol	Parameter	Conditions	Value	Unit
R <sub>th(j-c)</sub>	thermal resistance from junction to case	final stage; $T_{case} = 90  ^{\circ}C$ ; $P_{L} = < tbd>$	[1] <tbd></tbd>	K/W
		driver stage; $T_{case} = 90  ^{\circ}C$ ; $P_{L} = < tbd>$	[1] <tbd></tbd>	K/W

<sup>[1]</sup> When operated with a CW signal.

### 7. Characteristics

Table 6. DC characteristics

 $T_{case}$  = 25 °C; per section unless otherwise specified.

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Final stag	ge					
V <sub>(BR)DSS</sub>	drain-source breakdown voltage	$V_{GS} = 0 \text{ V}; I_D = <\text{tbd}>$	<tbd></tbd>	-	-	V
$V_{GS(th)}$	gate-source threshold voltage	$V_{DS} = 10 \text{ V}; I_D = <\text{tbd}>$	<tbd></tbd>	<tbd></tbd>	<tbd></tbd>	V
$V_{GSq}$	gate-source quiescent voltage	$V_{DS} = 28 \text{ V}; I_D = <\text{tbd}>$	<tbd></tbd>	<tbd></tbd>	<tbd></tbd>	V
I <sub>DSS</sub>	drain leakage current	$V_{GS} = 0 \text{ V}; V_{DS} = 28 \text{ V}$	-	-	<tbd></tbd>	μΑ
$I_{DSX}$	drain cut-off current	$V_{GS} = V_{GS(th)} + 3.75 \text{ V}; V_{DS} = 10 \text{ V}$	-	<tbd></tbd>	-	Α
$I_{GSS}$	gate leakage current	$V_{GS} = 11 \text{ V}; V_{DS} = 0 \text{ V}$	-	-	<tbd></tbd>	nΑ
9 <sub>fs</sub>	forward transconductance	$V_{DS} = 10 \text{ V}; I_D = <\text{tbd}>$	-	<tbd></tbd>	-	S
R <sub>DS(on)</sub>	drain-source on-state resistance	$V_{GS} = V_{GS(th)} + 3.75 \text{ V}; I_D = < tbd>$	-	<tbd></tbd>	-	$m\Omega$
$I_{Dq}$	quiescent drain current	$V_{DS} = 28 \text{ V}$	<tbd></tbd>	<tbd></tbd>	<tbd></tbd>	mΑ
Driver sta	age					
$V_{(BR)DSS}$	drain-source breakdown voltage	$V_{GS} = 0 \text{ V}; I_D = <\text{tbd}>$	<tbd></tbd>	-	-	V
$V_{GS(th)}$	gate-source threshold voltage	$V_{DS} = 10 \text{ V}; I_D = <\text{tbd}>$	<tbd></tbd>	<tbd></tbd>	<tbd></tbd>	V
$V_{GSq}$	gate-source quiescent voltage	$V_{DS} = 28 \text{ V}; I_D = <\text{tbd}>$	<tbd></tbd>	<tbd></tbd>	<tbd></tbd>	V
I <sub>DSS</sub>	drain leakage current	$V_{GS} = 0 \text{ V}; V_{DS} = 28 \text{ V}$	-	-	<tbd></tbd>	μΑ
I <sub>DSX</sub>	drain cut-off current	$V_{GS} = V_{GS(th)} + 3.75 \text{ V}; V_{DS} = 10 \text{ V}$	-	<tbd></tbd>	-	Α
I <sub>GSS</sub>	gate leakage current	$V_{GS} = 11 \text{ V}; V_{DS} = 0 \text{ V}$	-	-	<tbd></tbd>	nΑ
9 <sub>fs</sub>	forward transconductance	$V_{DS} = 10 \text{ V}; I_D = <\text{tbd}>$	-	<tbd></tbd>	-	S
R <sub>DS(on)</sub>	drain-source on-state resistance	$V_{GS} = V_{GS(th)} + 3.75 \text{ V; } I_D = < tbd>$	-	<tbd></tbd>	-	$m\Omega$
I <sub>Dq</sub>	quiescent drain current	V <sub>DS</sub> = 28 V	<tbd></tbd>	<tbd></tbd>	<tbd></tbd>	mΑ

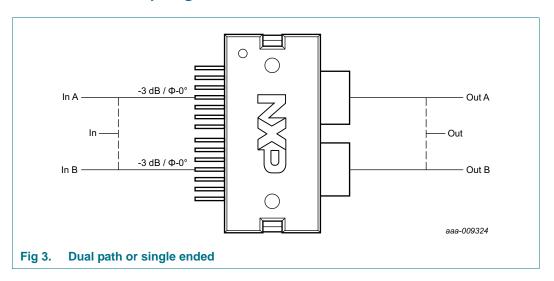
#### Table 7. RF Characteristics

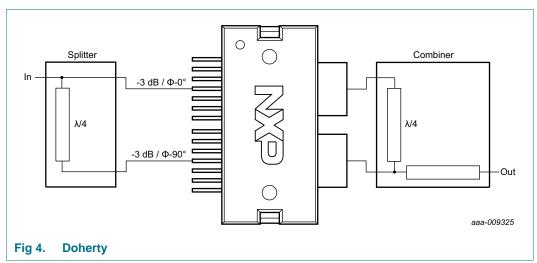
Typical RF performance at  $T_{\rm case} = 25~{}^{\circ}{\rm C};~V_{\rm DS} = 28~V;~I_{\rm Dq1} = <tbd>, <math>I_{\rm Dq2} = <tbd>$ . Test signal: 2-carrier W-CDMA; 3GPP test model 1; 64 DPCH; clipping at 46 %; PAR = 8.4 dB at 0.01% probability on CCDF per carrier; carrier spacing = 5 MHz;  $f = 2140~{\rm MHz}$ ; per section unless otherwise specified, measured in a class-AB production circuit.

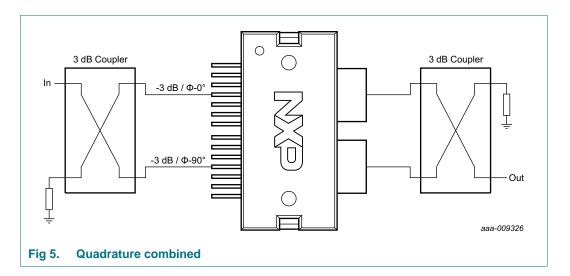
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Gp	power gain	$P_{L(AV)} = 0.5 \text{ W}$	<tbd></tbd>	31.5	<tbd></tbd>	dB
$\eta_{D}$	drain efficiency	$P_{L(AV)} = 0.5 \text{ W}$	<tbd></tbd>	12	-	%
RLin	input return loss	$P_{L(AV)} = 0.5 W$	-	<b>–15</b>	<tbd></tbd>	dB
ACPR	adjacent channel power ratio	$P_{L(AV)} = 0.5 W$	-	<tbd></tbd>	<tbd></tbd>	dBc

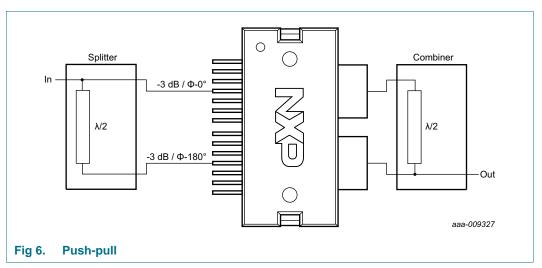
# 8. Application information

### 8.1 Possible circuit topologies









### 9. Package outline

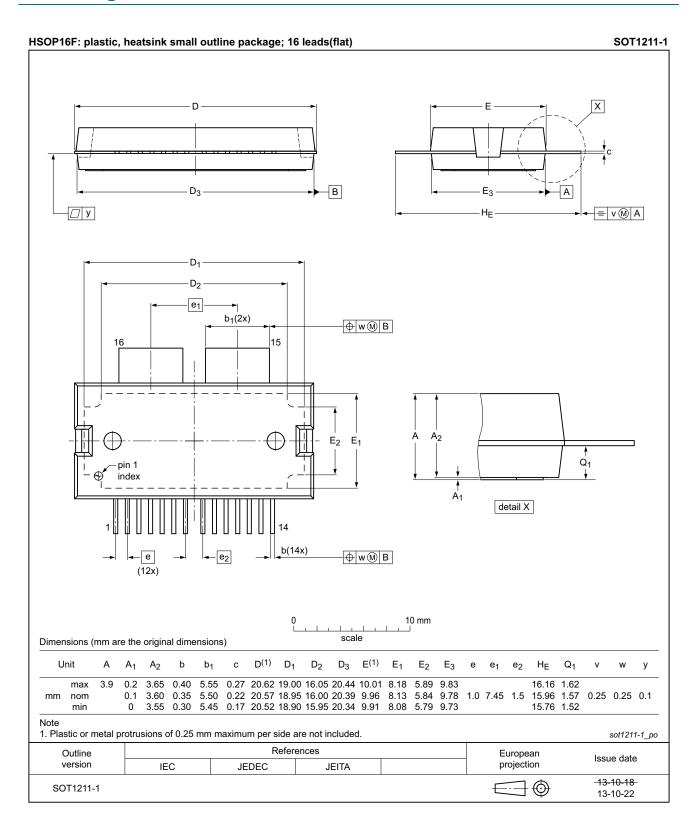


Fig 7. Package outline SOT1211-1 (HSOP16F)

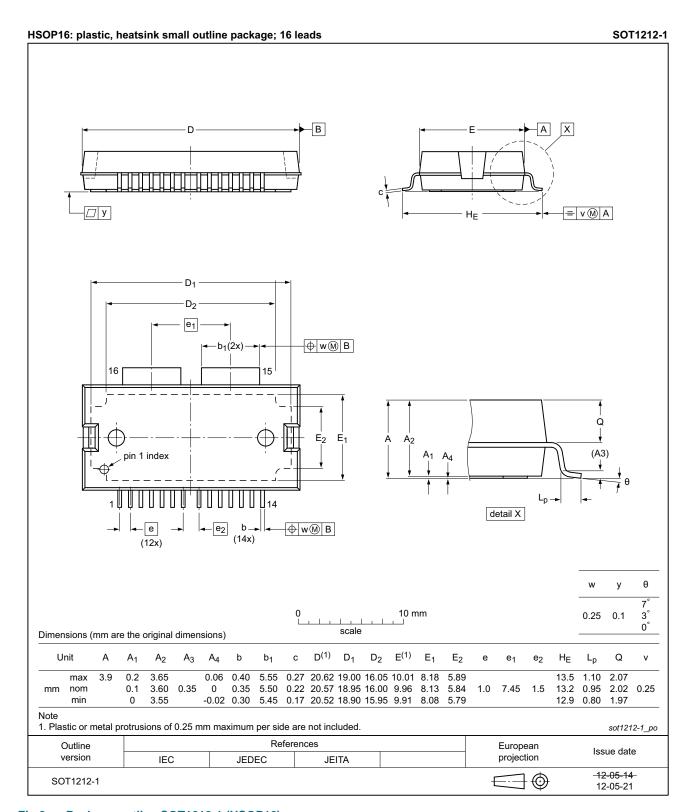


Fig 8. Package outline SOT1212-1 (HSOP16)

### 10. Handling information

### CAUTION



This device is sensitive to ElectroStatic Discharge (ESD). Observe precautions for handling electrostatic sensitive devices.

Such precautions are described in the ANSI/ESD S20.20, IEC/ST 61340-5, JESD625-A or equivalent standards.

### 11. Abbreviations

Table 8. Abbreviations

Acronym	Description
3GPP	3rd Generation Partnership Project
CCDF	Complementary Cumulative Distribution Function
CW	Continuous Wave
DPCH	Dedicated Physical CHannel
ESD	ElectroStatic Discharge
GEN7	Seventh Generation
LDMOS	Laterally Diffused Metal Oxide Semiconductor
MMIC	Monolithic Microwave Integrated Circuit
MTF	Median Time to Failure
PAR	Peak-to-Average Ratio
W-CDMA	Wideband Code Division Multiple Access

### 12. Revision history

Table 9. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
BLM7G1822S-20PB_S-20PBG v.1	20131219	Objective data sheet	-	-

### 13. Legal information

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Document status[1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
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# **BLM7G1822S-20PB(G)**

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